

Thursday, July 26, 2018

POSTER SESSION II: DEVELOPMENTS IN ANALYTICAL TECHNIQUE FOR  
METEORITE AND RETURNED SAMPLE ANALYSIS

5:30 p.m. Foyer

Snead C. J. Rahman Z. McCubbin F. M.

[Using Focused Ion Beam Milling to Modify Conductive and Charge-Dissipative Substrates for Microparticle Storage and Characterization](#) [#6321]

We report a technique for using a Focused Ion Beam (FIB) to mill wells in a silicon chip for particle storage and e-beam characterization.

Zanetta P.-M. Leroux H. Le Guillou C. Manda B. Hewins R. H. Lewin E. Pont S.

[Modal Abundance, Chemistry and Density of Chondrites Fine Grained Materials by Advanced Electron Microscopy](#) [#6204]

We developed a new methodology to compare the modal mineralogy, the composition and the density variations of fine grained materials of primitive chondrites. This methodology has been applied to the fine grained rims of Paris in another abstract.